On behalf of the members of the organizing committee of the 2002 Asian Test Symposium (ATS’02), I would like to welcome you to the Eleventh Asian Test Symposium, being held in Guam. It has passed ten years since the first Asian Test Symposium started in 1992 in Hiroshima, Japan. Through these ten years, we have held Asian Test Symposia in different cities in Asian countries and regions; Hiroshima (Japan), Beijing (China), Nara (Japan), Bangalore (India), Hsinchu (Taiwan), Akita (Japan), Singapore (Singapore), Shanghai (China), Taipei (Taiwan) and Kyoto (Japan). This time our symposium place is in Guam, USA. Guam belongs to the USA, but it belongs to region 10 of the IEEE category, which belongs to the Asian and Pacific region. Neither VLSI industries nor electronics industries exist on this island, however, circumstances surrounded by the emerald sea is one of the best places to have a symposium, just like new ideas will often be created in the park while taking a walk.

During these ten years the density of integration increased 13 times and VLSI design has come to the deep submicron age. With such rapid advances and developments in electronics technology and with continued shrinking of the device dimensions, testing of new devices has become more and more important. ATS is one of the major forums for discussing the solutions arising due to such rapid developments in the VLSI technology. In Guam’s comfortable atmosphere, ATS’02, as the first ATS of the second decade, will provide a good opportunity for researchers and academics to exchange and discuss new ideas and present new research results. We hope that this exchange will bring new impact on the research activities and contribute to the development of the testing field.

Success of a symposium depends on a strong technical program and requires a lot of effort and support. The Program Committee, under the leadership of Professor Kiyoshi Furuya, has carefully evaluated and selected 72 papers from 12 different countries. I would like to express my thanks to the members of the organizing and program committees for all the time and effort they have spent in creating this Symposium. Also, I would like to express my gratitude to Professor Paulo Prinetto and all members of the Test Technology Technical Council for their heartfelt support.

I hope those attending this symposium will also find much of interest in the cultural and natural climate of Guam, and ATS’02 will be an enjoyable symposium for all the attendees.

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